Se	arc	h N	otes
			



Application/Control No.	Applicant(s)/Patent under Reexamination
10/623,067	LIAU, ERIC
Examiner	Art Unit
Binh C. Tat	2825

SEARCHED				
Class	Subclass	Date	Examiner	
716	1-6, 16-18	4/30/2005	вт	
714	39	4/30/2005	ВТ	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
716	4,5	4/30/2005	вт
714	39	4/30/2005	ВТ

SEARCH (INCLUDING SEA	I NOTES RCH STRATEGY)
	DATE	EXMR
EAST SEARCH	4/30/2005	ВТ
IEEE .	4/30/2005	ВТ
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